# **Power MOSFET**

# 40 V, 2.5 m $\Omega$ , 130 A, Single N-Channel

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb-Free and are RoHS Compliant

# **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	40	V
Gate-to-Source Voltage			$V_{GS}$	±20	V
Continuous Drain		T <sub>C</sub> = 25°C		130	Α
Current R <sub>0JC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		81	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	69	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		28	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	27	Α
Current R <sub>θJA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		17	
Power Dissipation	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	3.1	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C		1.2	
Pulsed Drain Current	$T_A = 25^\circ$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	77	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 10 A)			E <sub>AS</sub>	265	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T <sub>L</sub>	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{ heta JC}$	1.8	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	41	

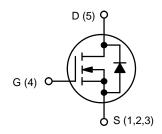
- 1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface–mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



## ON Semiconductor®

#### www.onsemi.com

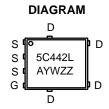
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
40 V	2.5 mΩ @ 10 V	420.4
40 V	$3.7~\text{m}\Omega$ @ $4.5~\text{V}$	130 A



**N-CHANNEL MOSFET** 



DFN5 (SO-8FL) CASE 488AA STYLE 1



**MARKING** 

5C442L = Specific Device Code = Assembly Location

= Year

= Work Week W ZZ = Lot Traceability

#### ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

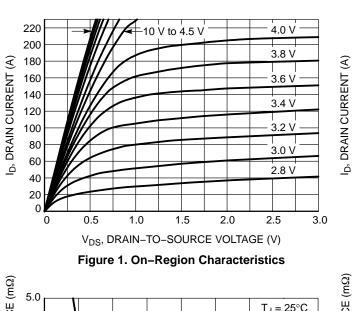
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•			•			•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				24.8		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$	T <sub>J</sub> = 25 °C			10	Δ.
		$V_{DS} = 40 \text{ V}$	T <sub>J</sub> = 125°C			250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$		1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.4		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		2.0	2.5	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 50 A		2.9	3.7	
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 50 A			116		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE						
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 25 V			3100		pF
Output Capacitance	Coss				1100		
Reverse Transfer Capacitance	C <sub>RSS</sub>				37		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 32 \text{ V}; I_D = 50 \text{ A}$			23		
Total Gate Charge	$Q_{G(TOT)}$	$V_{GS} = 10 \text{ V}, V_{DS} = 32 \text{ V}; I_D = 50 \text{ A}$			50		1
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 32 V; I <sub>D</sub> = 50 A			5.0		nC
Gate-to-Source Charge	Q <sub>GS</sub>				9.8		
Gate-to-Drain Charge	$Q_{GD}$				6.7		
Plateau Voltage	$V_{GP}$				3.1		V
SWITCHING CHARACTERISTICS (Note:	5)			•		•	•
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 32 \text{ V},$ $I_{D} = 50 \text{ A}, R_{G} = 1.0 \Omega$			12		ns
Rise Time	t <sub>r</sub>				72		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				28		
Fall Time	t <sub>f</sub>				8.4		
DRAIN-SOURCE DIODE CHARACTERIS	STICS				•		•
Forward Diode Voltage	V <sub>SD</sub>	$V_{GS} = 0 \text{ V},$ $I_{S} = 50 \text{ A}$	T <sub>J</sub> = 25°C		0.85	1.2	
			T <sub>J</sub> = 125°C		0.73		V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dI}_{S}/dt = 100 \text{ A}/\mu\text{s,}$ $I_{S} = 50 \text{ A}$			46		
Charge Time	ta				23		ns
Discharge Time	t <sub>b</sub>				23		
Reverse Recovery Charge	Q <sub>RR</sub>				40		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

#### TYPICAL CHARACTERISTICS



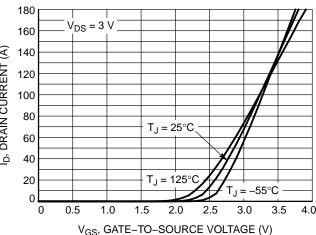
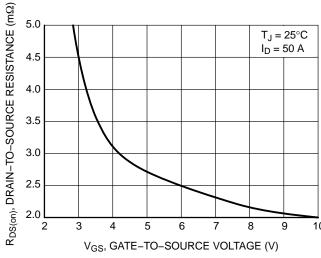


Figure 2. Transfer Characteristics



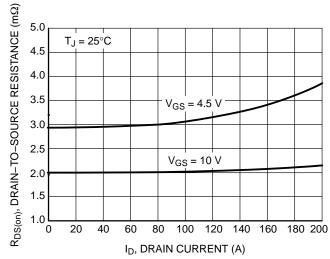
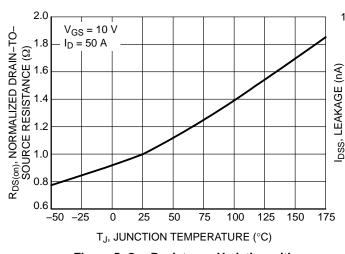


Figure 3. On–Resistance vs. Gate–to–Source Voltage

Figure 4. On–Resistance vs. Drain Current and Gate Voltage



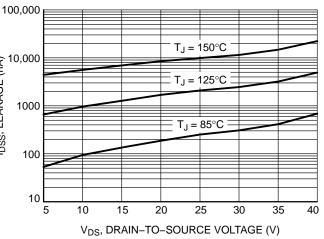
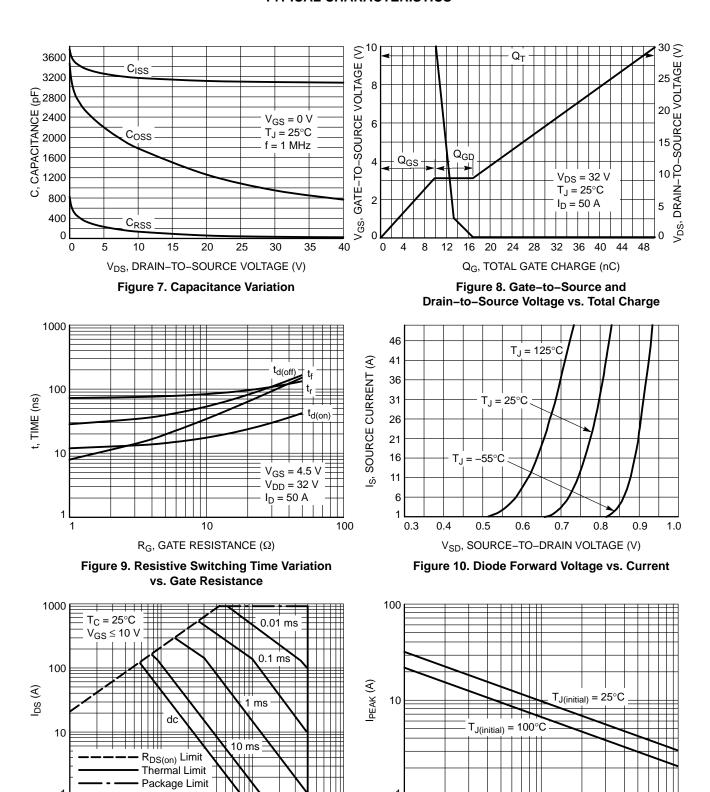


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### TYPICAL CHARACTERISTICS



 $\label{eq:VDS} V_{DS}\left(V\right)$  Figure 11. Safe Operating Area

10

0.1

TIME IN AVALANCHE (s) Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

1E-03

1E-02

100

1E-04

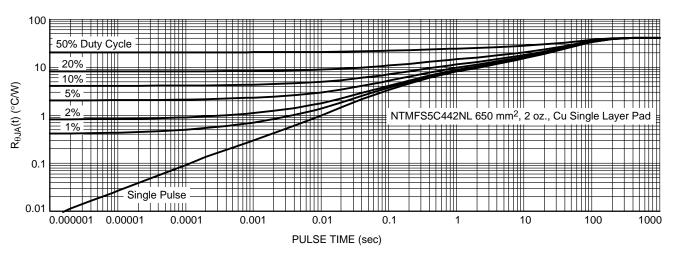


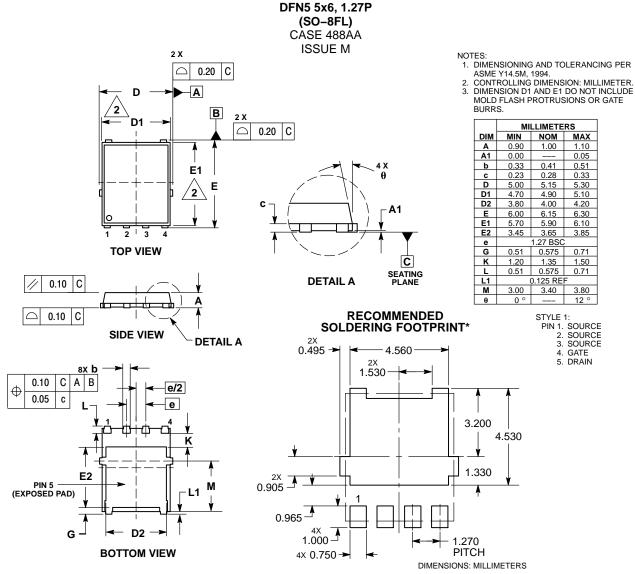
Figure 13. Thermal Characteristics

## **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTMFS5C442NLT1G	5C442L	DFN5 (Pb-Free)	1500 / Tape & Reel
NTMFS5C442NLT3G	5C442L	DFN5 (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and the are registered trademarks of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries. SCILLC owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of SCILLC's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding

#### **PUBLICATION ORDERING INFORMATION**

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303–675–2175 or 800–344–3860 Toll Free USA/Canada Fax: 303–675–2176 or 800–344–3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center

Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

# **Mouser Electronics**

**Authorized Distributor** 

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

**ON Semiconductor:** 

NTMFS5C442NLT1G NTMFS5C442NLT3G